Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/644,809	OKAWA ET AL.	
Examiner	Art Unit	
Huy D. Nguyen	2681	

	SEARCHED						
Cla	iss	Subclass	Da	Date		Examiner	
45	55	25	6/3/2	6/3/2005 HN		łΝ	
		63.4					
		82					
		562.1					
		575.7					
		121					
		129					
		101					
		13.3					
		19					
		406					
34	2	367					
		368					
		354					

INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
455	562.1	6/3/2006	HN		
	575.7				
	25				

SEARCH NOTES (INCLUDING SEARCH STRATEGY)					
	DATE	EXMR			
East; Text Search	6/3/2005	HN			
East (USPAT, US-PGPUB, EPO, JPO, DERWENT) - see search history printout.	11/21/2005	ни			
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See interference search printout.	5/10/2006	HN			
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